

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/771,826	<b>Applicant(s)/Patent under Reexamination</b> FENG, KAI D.
	<b>Examiner</b> Anh Q. Tran	<b>Art Unit</b> 2819

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner